WHAT IS CLAIMED IS:

- 1. An electron source forming substrate comprising an insulating material film provided on a substrate surface where an electron-emitting device is arranged, wherein said insulating material film contains a metallic oxide and has a vacancy.
- 2. The electron source forming substrate according to claim 1, wherein said metallic oxide is an electronically conductive oxide.
- 3. The electron source forming substrate according to claim 1, wherein said metallic oxide is $2\sqrt{100}$ SnO₂.

4. The electron source forming substrate

according to any one of claims 1 to 3, wherein said
insulating material film has a ratio of said vacancy in
its cross section within the range of 5% to 10%.

5. The electron source forming substrate according to any one of claims 1 to 3, wherein a thickness of said insulating material film is within the range of 150 nm to 3 μ m.

6. The electron source forming substrate 'a 2/

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according to any one of claims 1 to 3, wherein said insulating material film further contains phosphorus.

- 7. The electron source forming substrate

 5 according to any one of claims 1 to 3, wherein the insulating material of said insulating material film is SiO₂. 15,15,20 (50), 51
- 8. The electron source forming substrate

 10 according to any one of claims 1 to 3, wherein on said insulating material film, a film comprising an insulating material is further laminated.
- 9. The electron source forming substrate
 15 according to claim 8, wherein the thickness of the film comprising said insulating material is within the range of 20 nm to 3 µm.
- 10. The electron source forming substrate 20 according to claim 8, wherein said insulating material is SiO_2 .
- 11. An electron source forming substrate
 comprising an insulating material film provided on a
 substrate surface where a electron emitting device is
 arranged, wherein said insulating material film

contains a plurality of metallic oxide particles and vacancy are provided among said plurality of metallic oxide particles.

- 12. The electron source forming substrate according to claim 11, wherein said insulating material film has a ratio of said vacancy in its cross section within the range of 5% to 10%.
- 13. The electron source forming substrate according to claim 11 or 12, wherein the thickness of said insulating material film is within the range of 150 nm to 3 μm .
- 14. The electron source forming substrate according to any one of claims 11 or 12, wherein said insulating material film further contains phosphorus.
- 15. The electron source forming substrate
 20 according to any one of claims 11 or 12, wherein the insulating material of said insulating material film is SiO₂.
- 16. The electron source forming substrate
 25 according to any one of claims 11 or 12, wherein on said insulating material film, a film comprising an

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insulating material is further laminated.

- 17. The electron source forming substrate according to claim 16, wherein the thickness of the film made of said insulating material is within the range of 20 nm to 3 μm .
- 18. The electron source forming substrate according to claim 16, wherein said insulating material 10 is SiO₂.
 - 19. An electron source forming substrate comprising an insulating material film provided on a substrate surface where an electron emitting device is arranged, wherein said insulating material film contains a plurality of metallic oxide particles, said plurality of the contained metallic oxide particles form a metallic oxide particle layer between said substrate surface and said insulating material film surface in said insulating material film, and vacancy is provided in said metallic oxide particle layer.
 - 20. The electron source forming substrate according to claim 19, wherein said metallic oxides particle layer has a ratio of said vacancy in its cross section within the range of 5% to 10%.

- 21. The electron source forming substrate according to claim 19 or 20, wherein said insulating material film further contains phosphorus.
- 22. The electron source forming substrate according to claim 19 or 20, wherein the insulating material of said insulating material film is SiO₂.
- 23. The electron source forming substrate according to claim 11 or 19, wherein the average particle size of said plurality of metallic oxide particles is within the range of 6 nm to 60 nm.
- 24. The electron source forming substrate according to claim 11 or 19, wherein the average particle size of said plurality of metallic oxide particles is within the range of 6 nm to 20 nm.
- 25. The electron source forming substrate according to claim 11 or 19, wherein the size of said vacancy is within the range of 0.1 to 5 times the average particle size of said plurality of metallic oxide particles.
- 26. The electron source forming substrate
 25 according to claim 11 or 19, wherein the size of said
 vacancy is within the range of 0.1 to 2 times the

average particle size of said plurality of metallic oxide particles.

- 27. The electron source according to claim 11 or 19, wherein said metallic oxide particles are electronically conductive particles.
 - 28. The electron source forming substrate according to claim 11 or 19, wherein said metallic oxide particles are particles of SnO₂.
 - 29. The electron source forming substrate according to any one of claims 1, 11 or 19, wherein said substrate is a substrate containing sodium.

30. The electron source forming substrate according to claim 29, wherein said insulating material film is a sodium blocking film.

- 20 31. The electron source forming substrate according to any one of claims 1, 11 or 19, wherein said insulating material film is a antistatic film.
- 32. An electron source, comprising a substrate
 and an electron-emitting device arranged on said
 substrate, wherein said substrate is the electron

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source forming substrate according to any one of claims 1, 11 or 19.

- 33. The electron source according to claim 32, wherein said electron-emitting device is an electron-emitting device comprising an conductive film including an electron-emitting portion.
- 34. The electron source according to claim 32, wherein a plurality of said electron-emitting devices are matrix-wired by a plurality of row-directional wirings and a plurality of column-directional wirings.
- 35. An image display apparatus comprising an electron-emitting device an image display member for displaying images by inradiation of electron from said electron-emitting device and an envelope in which said electron-emitting device and said image display member are arranged, wherein a substrate where said electron-emitting device is arranged are electron source forming substrate according to any one of claims 1, 11 or 19.
- 36. The image display apparatus according to claim 35, wherein said electron-emitting devices are electron-emitting devices comprising an conductive film containing the electron-emitting portion.

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37. The image display apparatus according to claim 35, wherein a plurality of said electron-emitting devices are matrix-wired by a plurality of row-directional wirings and a plurality of column-directional wirings.

